



ALPHA & OMEGA
SEMICONDUCTOR

AON6413

30V P-Channel MOSFET

General Description

- Latest Trench Power MOSFET technology
- Very Low $R_{DS(ON)}$ at 4.5V V_{GS}
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

Application

- System/Load Switch, Battery Switch

Product Summary

V_{DS}	-30V
I_D (at $V_{GS}=-10V$)	-32A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 8.5mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 17mΩ

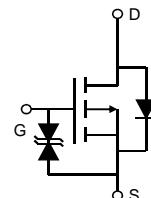
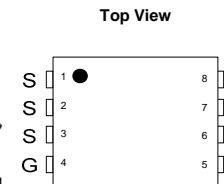
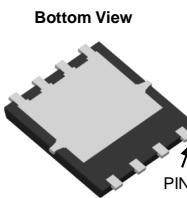
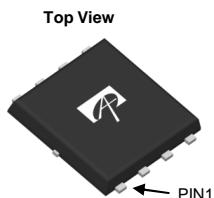
Typical ESD protection

HBM Class 3A

100% UIS Tested
100% R_g Tested



DFN5X6



Orderable Part Number

AON6413

Package Type

DFN 5x6

Form

Tape & Reel

Minimum Order Quantity

3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current ^G	I_D	-32	A
$T_C=100^\circ C$		-25	
Pulsed Drain Current ^C	I_{DM}	-128	
Continuous Drain Current	I_{DSM}	-22	A
$T_A=70^\circ C$		-17	
Avalanche Current ^C	I_{AS}	-40	A
Avalanche energy $L=0.1mH$ ^C	E_{AS}	80	mJ
V_{DS} Spike	10μs	V_{SPIKE}	V
Power Dissipation ^B	$T_C=25^\circ C$	48	W
	$T_C=100^\circ C$	19	
Power Dissipation ^A	$T_A=25^\circ C$	6.2	W
	$T_A=70^\circ C$	4	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	2.1	2.6	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		-1	-5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm25\text{V}$			±10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.6	-2.1	-2.7	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-16\text{A}$ $T_J=125^\circ\text{C}$		6.9	8.5	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-10\text{A}$		9.8	12	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-16\text{A}$		-47		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current ^G				-32	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		2142		pF
C_{oss}	Output Capacitance			474		pF
C_{rss}	Reverse Transfer Capacitance			363		pF
R_g	Gate resistance	$f=1\text{MHz}$		2.3	4.6	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-16\text{A}$		41	58	nC
$Q_g(4.5\text{V})$	Total Gate Charge			18.5	27	nC
Q_{gs}	Gate Source Charge			15		nC
Q_{gd}	Gate Drain Charge			6		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=0.9\Omega, R_{\text{GEN}}=3\Omega$		13		ns
t_r	Turn-On Rise Time			12		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			34		ns
t_f	Turn-Off Fall Time			18.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-16\text{A}, dI/dt=500\text{A}/\mu\text{s}$		17.5		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-16\text{A}, dI/dt=500\text{A}/\mu\text{s}$		44.5		nC

A. The value of $R_{\text{DS(on)}}$ is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation $P_{\text{DS(on)}}$ is based on $R_{\text{DS(on)}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.

D. The $R_{\text{DS(on)}}$ is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

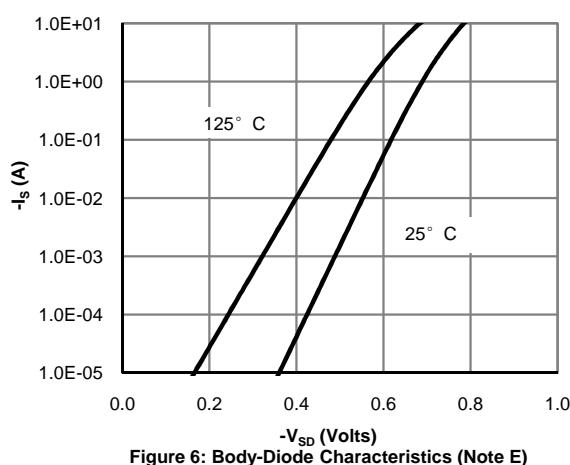
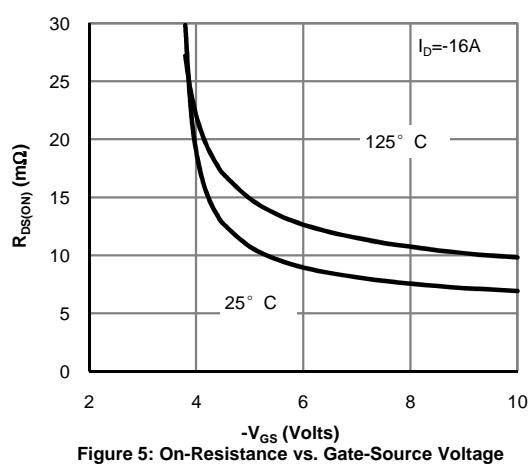
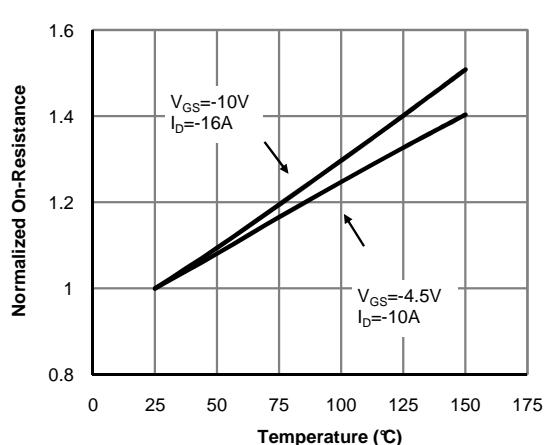
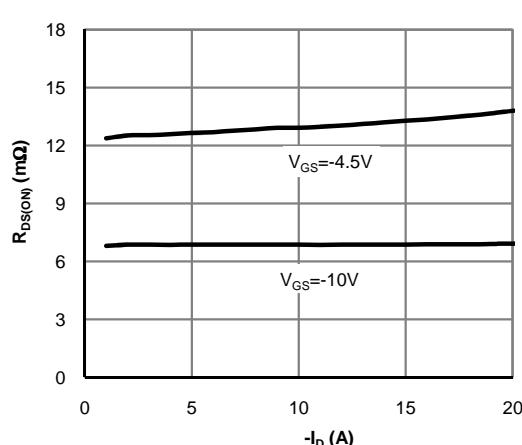
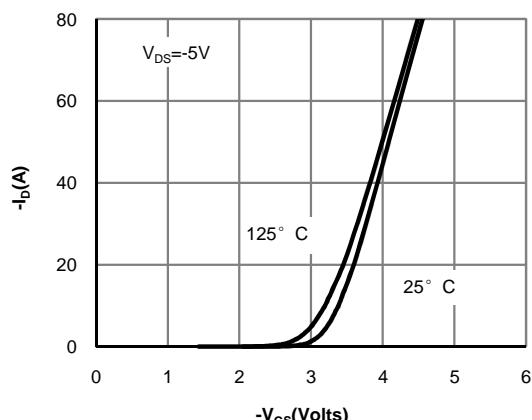
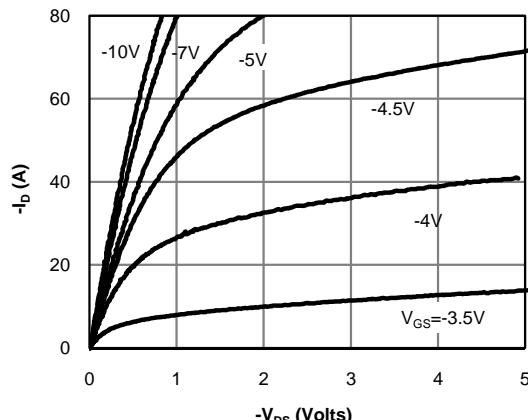
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

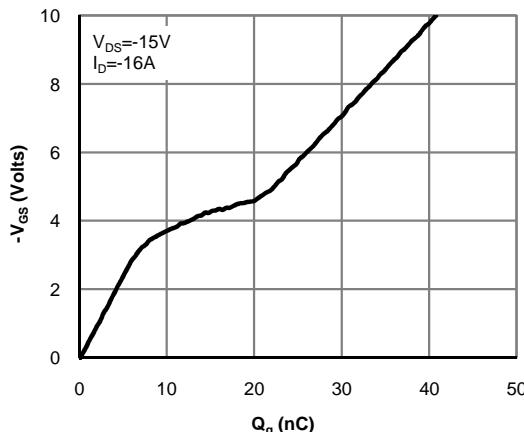
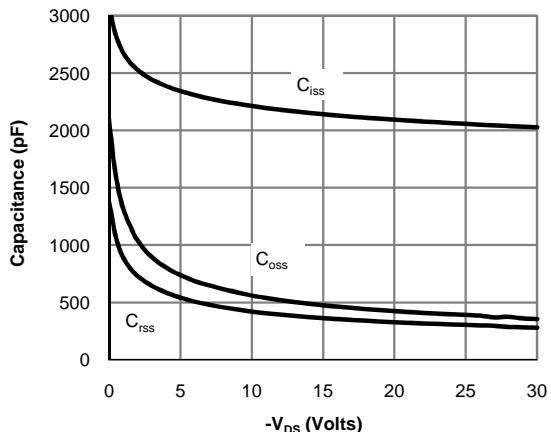
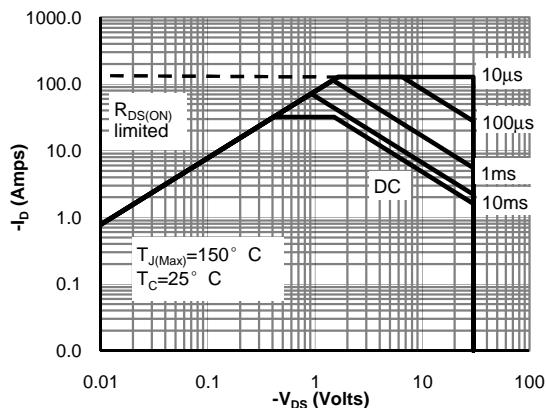
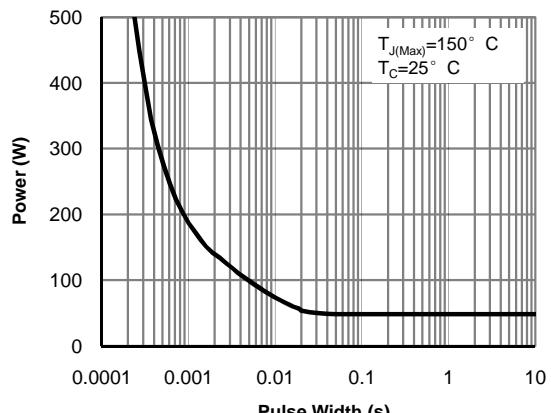
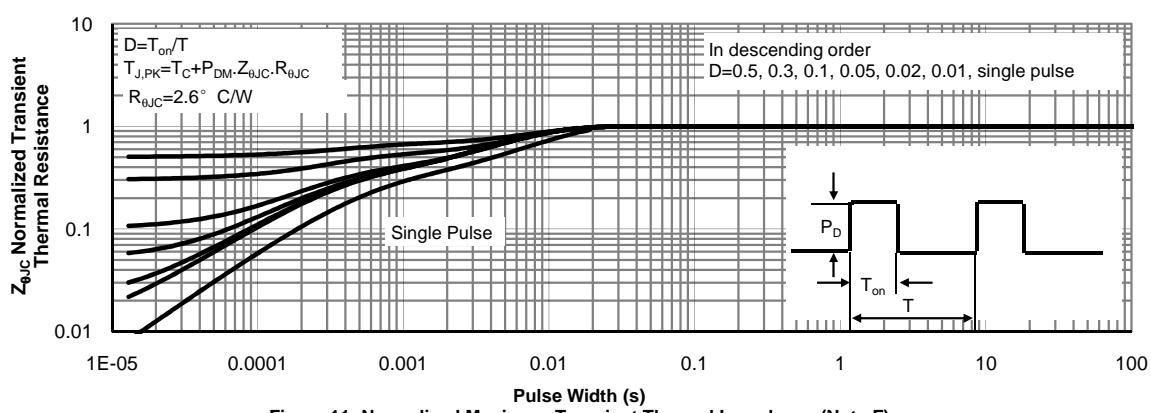
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


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Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

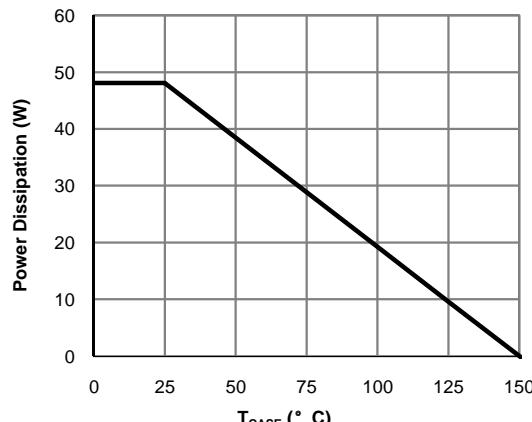
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

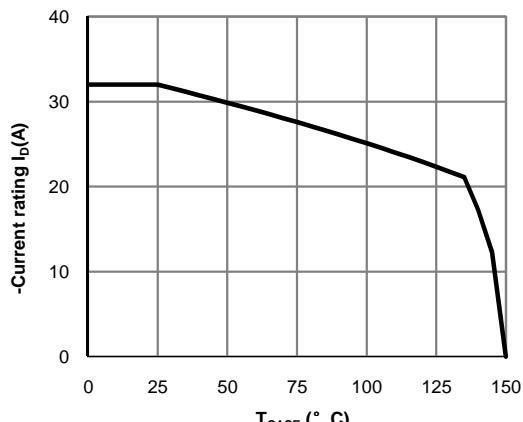


Figure 13: Current De-rating (Note F)

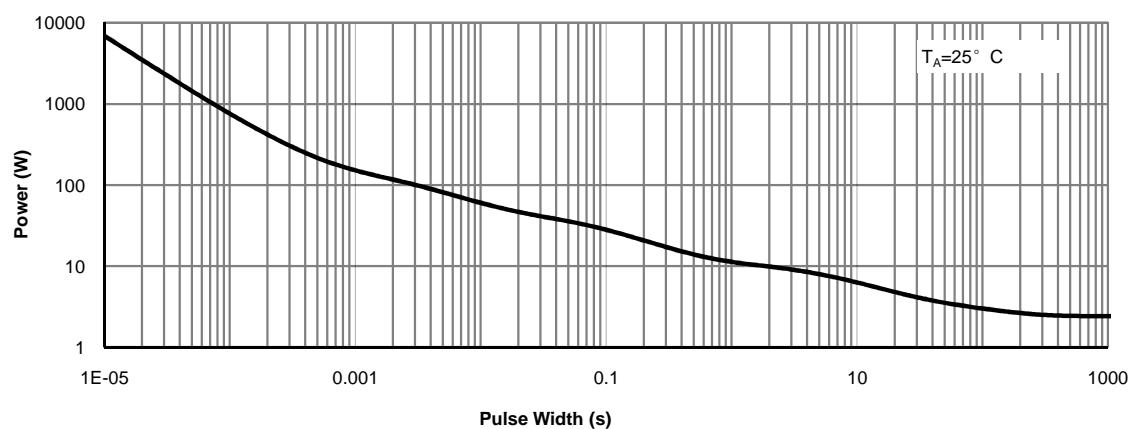


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

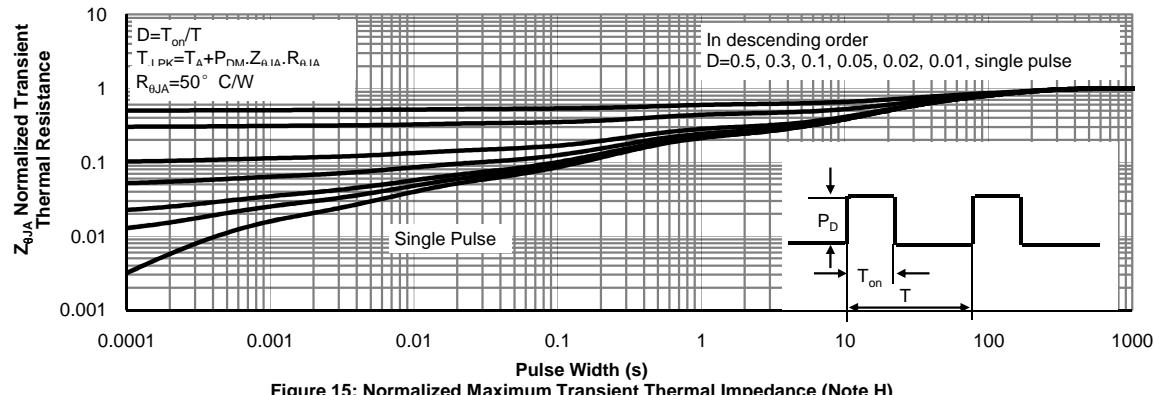
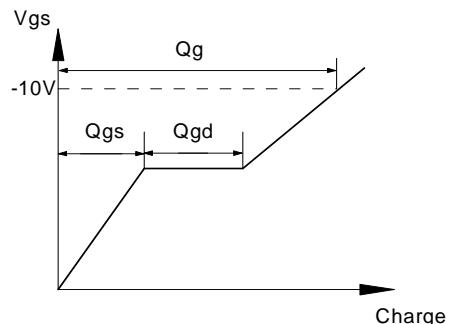
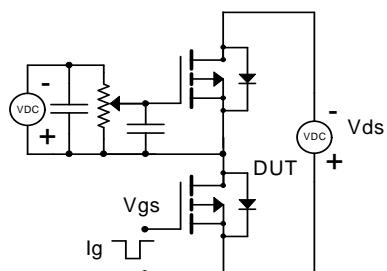
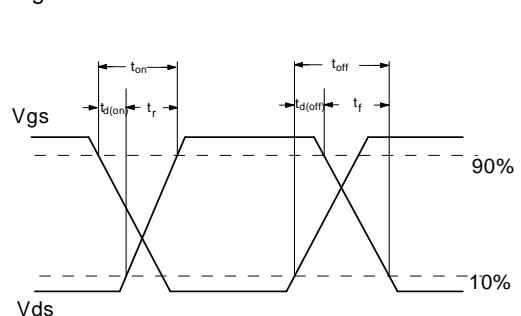
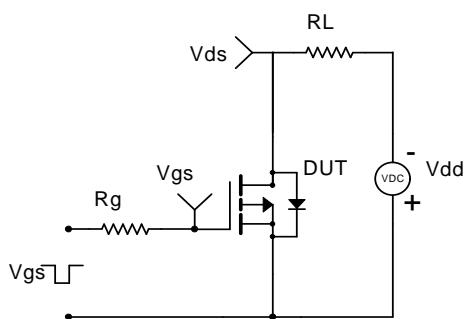


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

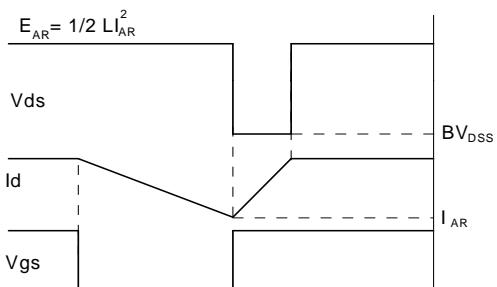
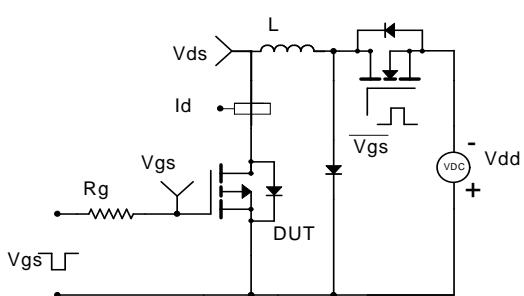
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

